Searcn Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/672,035	KANG ET AL.
Examiner	Art Unit
Thien F. Tran	2811

SEARCHED				
Class	Subclass	Date	Examiner	
257	529, 530 209, 665	8/10/2005	īΤ	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
		DATE	EXMR	
EAST		8/10/2005	π	
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